Electronic Supplementary Material (ESI) for ChemComm. This journal is © The Royal Society of Chemistry 2023

## **Electronic Supporting Information (ESI)**

## Enhanced Li-Ion Conductivity in LiBH<sub>4</sub>-ZrO<sub>2</sub> Nanocomposites and Nanoscale Li Imaging by Energy-Filtered Transmission Electron Microscopy

Yuki Nakagawa,<sup>a\*</sup> Tsubasa Sendo,<sup>b</sup> Tamaki Shibayama<sup>a</sup>

<sup>a</sup> Faculty of Engineering, Hokkaido University, N-13, W-8, Sapporo, 060-8628, Japan
<sup>b</sup> Graduate School of Engineering, Hokkaido University, N-13, W-8, Sapporo, 060-8628, Japan

\* Corresponding Author E-mail: y-nakagawa@eng.hokudai.ac.jp (Y. Nakagawa)

## **Experimental Section**

All samples were handled in an argon-filled glovebox with an  $O_2$  level below 2 ppm. Micron ZrO<sub>2</sub> (~5  $\mu$ m, purity 99%, Aldrich) and nano ZrO<sub>2</sub> (<100 nm, purity N.A., surface area  $\geq$ 25 m<sup>2</sup>/g, Aldrich) powders were used as received. Mechanical milling was performed using a planetary ball-milling apparatus (Fritsch, Pulverisette 7, Cr-steel vessel with 15 zirconia balls). The ball-to-powder weight ratio was 84:1. LiBH<sub>4</sub> (purity  $\geq$  95%, Aldrich) was ball-milled at 500 rpm for 2 h in an Ar atmosphere. Then, ball-milled LiBH<sub>4</sub> and each ZrO<sub>2</sub> powder were mixed using a volume ratio of 3:1 (weight ratio of 1:3) by ball-milling at 300 rpm for 0.5 h in an Ar atmosphere. Heat treatment of samples were performed by using thermogravimetry-differential thermal analysis (TG-DTA, Bruker, 2000SA) under Ar atmosphere. The samples were heated to 140 °C with the heating rate of 5 °C/min and were kept at 140 °C for 30 min. Crystalline phases of samples were analyzed by X-ray diffraction (XRD, Rigaku MiniFlex with Cu Ka radiation). The XRD samples were covered with a polyimide sheet in the glovebox to avoid contact with air. For ion conductivity measurements and scanning electron microscopy (SEM), sample powders were pressed into a pellet (7 mm,  $\sim$ 2 mm thick). Ion conductivities were measured using an alternatingcurrent impedance analyzer (HIOKI IM3536, 4 Hz-8 MHz). Lithium foils (purity 99.9%, Alfa Aesar, thickness of 0.75 mm) were used as electrodes. The cross-sectional images of the pellets were observed by field emission gun SEM (FESEM, JEOL, JSM-7001FA) with an acceleration voltage of 15 kV. The cross-section of the pellets was obtained by cutting the sample using a pair of scissors in a glovebox. The samples were set on the specimen holder in the glovebox and then quickly transferred to the SEM chamber to minimize air exposure. Solid-state nuclear magnetic resonance (NMR) spectra were collected using a Bruker Avance Neo 500 spectrometer in a magnetic field of 11.74 T. Information about Li ion dynamics was collected using static <sup>7</sup>Li spectra. The 2.5 mm Bruker ZrO<sub>2</sub> rotors were filled with sample powders. The spectra were acquired in a single-pulse experiment with a pulse width of 4.0 µs. The chemical bonding states were analyzed by <sup>6</sup>Li and <sup>11</sup>B magic angle spinning (MAS) NMR spectra. The 3.2 and 2.5 mm ZrO<sub>2</sub> rotors were filled with sample powders for the <sup>6</sup>Li and <sup>11</sup>B MAS spectra measurements, respectively. The <sup>6</sup>Li and <sup>11</sup>B MAS spectra were recorded with spinning speeds of 20 and 15 kHz, respectively. Chemical shifts were calibrated using 1.0 M aqueous solutions of LiCl for <sup>6</sup>Li and NaBH<sub>4</sub> for <sup>11</sup>B. The <sup>6</sup>Li and <sup>11</sup>B MAS spectra were acquired with pulse lengths of 1.6 and 1.4 µs, and delay times of 10–30 and 5 s, respectively. Transmission electron microscopy (TEM) observations were conducted by Cs-corrected STEM (FEI, Titan) with an acceleration voltage of 300 kV. The sample powders were dispersed on a carbon film-coated grid (quantifoil) or a holey silicon nitride film-coated grid. Then, the grid was set to an Atmos Defend Holder (Phyla, Mel-Build) in the glovebox to transfer the specimen without exposure to air. Energy-filtered TEM (EFTEM) images were acquired using the elastic electrons, Li K-edge, B K-edge, and Zr M<sub>4.5</sub>-edge. The energies of the Li K-edge, B K-edge, and Zr M<sub>4.5</sub>-edge were 55, 188, and 180–182 eV, respectively. The three-window method was applied for the elemental mapping. The Li mapping was acquired with Li K-edge by inserting a slit length of 10 eV and using an exposure time of 5-30 s. Considering the close energies between the B K-edge and Zr M<sub>4.5</sub>-edge, the combined mapping from B and Zr was acquired with the Zr M<sub>4.5</sub>-edge by inserting a slit length of 20 eV and using an exposure time of 30-60 s. The energy-dispersive X-ray spectroscopy (EDS) analysis in STEM mode was performed using a beam current of 50 pA. TEM-electron energy loss spectra (EELS) were taken for the selected sample area.



Fig. S1 XRD profiles of 25 vol.% nano  $ZrO_2$  composite: (a) as synthesized, (b) after heating to 140 °C under Ar atmosphere, (c) after AC impedance measurements up to 140 °C.



**Fig. S2** Cross-sectional SEM images of 25 vol.% micron ZrO<sub>2</sub> composite pellets: (a) secondary electron image and (b) backscattered electron image.



Fig. S3 The corresponding unfiltered TEM image for 25 vol.% nano  $ZrO_2$  composite.



Fig. S4 TEM-EELS spectrum of as-synthesized 25 vol.% nano  $ZrO_2$  composite.



**Fig. S5** (a) HAADF-STEM image, (b) EDS mapping of B, (c) EDS mapping of Zr, (d) EDS mapping of O, (e) EDS spectrum of area 1 in Fig. S5(a), and (f) EDS spectrum of area 2 in Fig. S5(a).



**Fig. S6** (a) EFTEM zero-loss image, (b) EFTEM Li mapping, (c) EFTEM combined elemental mapping from B and Zr, and (d) HAADF-STEM image for 25 vol. % nano  $ZrO_2$  composite after ion conductivity measurements (heating to 140 °C). The Li K-edge was used for Li mapping, and the B K-edge and Zr M<sub>4,5</sub>-edge were used for the combined mapping. The particles were deposited on holey SiN films on the TEM grids, which is indicated in the upper-left corner of the images. The thickness of SiN film was ~200 nm.